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Applicant: Yong-Jun Hu

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U. S. PATENT DOCUMENTS

**Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
JN	4,394,196	07/19/1983	Iwai, H.	148	187	07/13/81
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JN	Ogawa, S., et al., "Dependence of Thermal Stability of the Titanium Silicide/Silicon Structure on Impurities", <u>Applied Physics Letters</u> , Vol. 56, No. 8, 725-727, (Feb. 19, 1990)
JN	Wehner, G.K., "The Aspects of Sputtering in Surface Analysis Methods", <u>Methods of Surface Analysis</u> , Elsevier Scientific, Vol. 1, 5-37, (1975)
JN	Wolf, S., et al., "Silicon Processing for the VLSI ERA", <u>Vol. 1, Process Technology</u> , Lattice Press, 367, (1986)

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JOSEPH NEVRIN

Date Considered

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*Substitute Disclosure Statement Form (PTO-1449)

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